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Understanding GaAs Native Oxides By Correlating Three Liquid Contact Angle Analysis (3LCAA) and High Resolution Ion Beam Analysis (HR-IBA) to X-Ray Photoelectron Spectroscopy (XPS) as Function of Surface Processing — ERRATUM

Sukesh Ram, Amber A. Chow, Shaurya Khanna, Nikhil C. Suresh, Francesca J. Ark, Saaketh R. Narayan, Aashi R. Gurijala, Jack M. Day, Timothy Karcher, Robert J. Culbertson, Shawn D. Whaley, Karen L. Kavanagh and Nicole Herbots

In the title of this article¹, the chemical formula “GaAs” was misspelled. This has been corrected in the original article.

The publisher regrets this error.

Reference:

1. S. Ram, A.A. Chow, S. Khanna, N.C. Suresh, F.J. Ark, S.R. Narayan, A.R. Gurijala, J.M. Day, T. Karcher, R.J. Culbertson, S.D. Whaley, K.L. Kavanagh, and N. Herbots, MRS Advances 1 (2019).